



Method of Detecting, Analyzing and Removal of Construction Defects in Residential Buildings

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Deadline for manuscript
submissions:

closed (30 March 2023)

Message from the Guest Editors

The aim of this Special Issue (SI) is to present modern solutions for diagnostics of buildings, monitoring the condition of structures, but also ways to repair defects and faults with the use of modern technologies and materials. An important aspect is also the management of the process of removing defects during construction, work acceptance, and the warranty and post-warranty period. This SI would act as an international platform to showcase emergent findings and contribute to generating new knowledge in this growing field of research.

This Special Issue welcomes various submission types, such as original research contributions, case studies, comparative studies, conceptual papers, and review studies.





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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